Notice of References Cited Application/Control No. 10/792,257 Examiner Nguyen T Ha Applicant(s)/Patent Under Reexamination STEYSKAL ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | Α | US-6,795,296 | 09-2004 | Palanduz et al. | 361/311 |
| | В | US-6,351,369 | 02-2002 | Kuroda et al. | 361/306.3 |
| | С | US-5,880,925 | 03-1999 | DuPre et al. | 361/303 |
| | D | US-6,421,227 | 07-2002 | Nitoh et al. | 361/523 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | Н | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | Р | | | | | |
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| | S | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.